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								Applicant Donald Dominic ARNONE et al.					
								Filing Date		Group Art Unit			
U.S. PATENT DOCUMENTS													
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FOREIGN PATENT DOCUMENTS													
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												Yes	No
	0	8	4	1	5	4	8	05/13/98	Europe				
	0	8	2	8	1	4	3	03/11/98	Europe				
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	0	8	6	4	8	5	7	09/16/98	Europe				
	2	2	5	4	4	1	7	10/07/92	Great Britain				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)													
	WU Q ET AL: "TWO-DIMENSIONAL ELECTRO-OPTIC IMAGING OF THZ BEAMS" APPLIED PHYSICS LETTERS, US, AMERICAN INSTITUTE OF PHYSICS. NEW YORK												
	vol. 69, no. 8, 19 August 1996 (1996-08-19), pages 1026-1028, XP000626128 ISSN: 0003-6951												
	PATENT ABSTRACTS OF JAPAN												
	vol. 13, no. 182 (C-591), 27 April 1989 (1989-04-27)												
	& JP 01 011530 A (HITACHI), 17 January 1989 (1989-01-17)												
	Abstract												
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